



Copia LLC

Consultants in Optical Science

James E. Leland, Principal
51 Ball Park Road, Goshen, NH 03752
jleland@copia-lux.com
603-504-2855

www.copia-lux.com

Copia LLC was founded to meet the needs of industry and government labs for accurate, reliable test and measurement of light sources, sensors, and optical materials. We bring our extensive light measurement experience to bear on your most critical challenges - in the laboratory, on the factory floor, or in the field.

SERVICES

- LABORATORY ASSESSMENT
- PRODUCT / PROCESS DEVELOPMENT
- TECHNICAL COMMUNICATION
- STANDARDS DEVELOPMENT
- TECHNICAL TRAINING

INDUSTRIES SERVED

- LED / SOLID-STATE LIGHTING
- DISPLAY: CONSUMER / AVIONICS
- TELECOMMUNICATIONS
- REMOTE SENSING
- TRAFFIC SAFETY

FIELDS of EXPERTISE

- SPECTRORADIOMETRY
- RADIOMETRY
- PHOTOMETRY
- COLORIMETRY
- IMAGING
- INTEGRATING SPHERE APPLICATIONS
- REFLECTANCE SPECTROSCOPY
- GONIOPHOTOMETRY
- RETROREFLECTION
- FLUORESCENCE



TECHNICAL TRAINING & COMMUNICATION

We provide technical training to professionals with diverse capabilities and backgrounds, ranging from production techs to sales reps to engineers and research scientists. We also work with clients to develop product and application literature that is useful, informative, and accessible to a wide audience.

ENGINEERING SERVICES

We support clients with critical optical test and measurement requirements by helping to design and specify equipment, develop appropriate procedures, and integrate them with existing quality systems. This enables our clients to verify compliance with product specifications as well as industrial and regulatory standards.



PROFILE: James E. Leland

Jim Leland has over twenty years' experience in radiometry, photometry, and related fields, and has authored numerous papers, patents, and industry standards. He has served on the executive boards of the Council for Optical Radiation Measurements (CORM) and the US National Committee of the CIE. He is an officer of ASTM E12 (Color and Appearance), chairing subcommittees E12.03 (Geometry), and E12.05 (Fluorescence). He is a member of SPIE, IES, and ISCC. He studied Physics and Philosophy at Princeton University, and holds an MS in Imaging Science from the Rochester Institute of Technology (RIT).